

SIGC104T170R2C

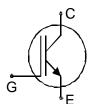
IGBT Chip in NPT-technology

FEATURES:

- 1700V NPT technology •
- 280µm chip •
- short circuit prove •
- positive temperature coefficient
- easy paralleling

This chip is used for:

- chip only •
- **Applications:** •
 - drives



Chip Type	V _{CE}	I Cn	Die Size	Package	Ordering Code
SIGC104T170R2C	1700V	50A	10.12 x 10.18 mm ²	sawn on foil	Q67041-A4695- A001

MECHANICAL PARAMETER:

Raster size	10.12 x 10.18			
Area total / active	103 / 71.5			
Emitter pad size	8x(1.78x2.58)			
Gate pad size	0.757 x 1.48			
Thickness	280	μm		
Wafer size	150	mm		
Flat position	90	deg		
Max.possible chips per wafer	130 pcs			
Passivation frontside	Photoimide			
Emitter metalization	3200 nm Al Si 1%			
Collector metalization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond	AI, ≤500µm			
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm			
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, Tj=25 °C	V _{CE}	1700	V
DC collector current, limited by T _{jmax}	I _C	1)	A
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	150	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I _C =3mA	1700			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =50A	2.2	2.7	3.2	V
Gate-emitter threshold voltage	V _{GE(th)}	I_C =2.2mA , V_{GE} = V_{CE}	4.5	5.5	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =1700V , V _{GE} =0V			12	μA
Gate-emitter leakage current	I _{GES}	$V_{CE}=0V$, $V_{GE}=20V$			300	nA
Integrated gate resistor	R _{Gint}			5		Ω

DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
Farameter	Symbol		min.	typ.	max.	Unit
Input capacitance	Ciss	V _{CE} =25V,	-	3.5	-	nF
Output capacitance	Coss	$V_{GE}=0V$,	-	tbd	-	
Reverse transfer capacitance	Crss	f=1MHz	-	tbd	-	

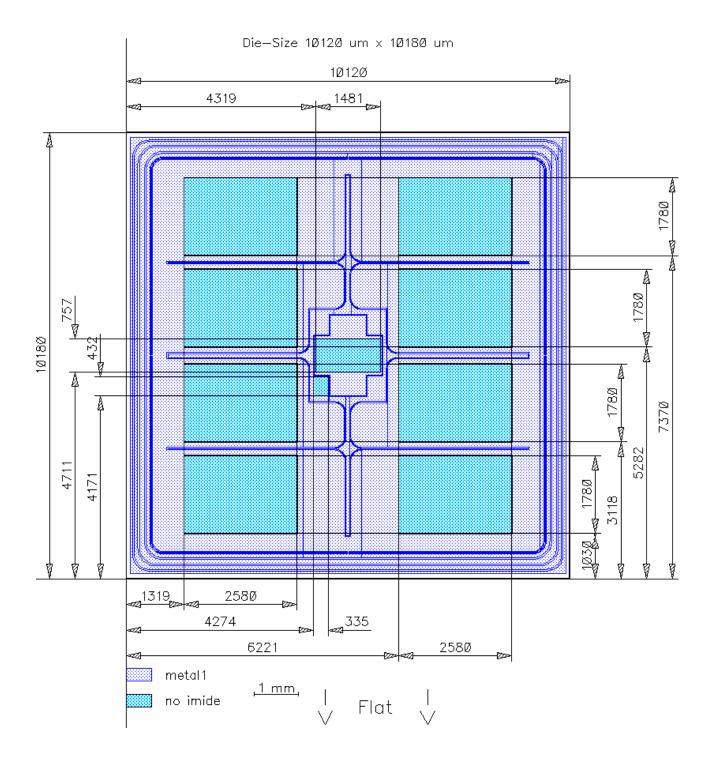
SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

Parameter	Symbol	Conditions ¹⁾	Value			Unit
			min.	typ.	max.	Onic
Turn-on delay time	t _{d(on)}	$T_{\rm j} = 125^{\circ}{\rm C}$	-	0.1	-	μs
Rise time	<i>t</i> r	V _{CC} =900V, I _C =50A	-	0.1	-	
Turn-off delay time	$t_{d(off)}$	V _{GE} =±15V, R _G =30Ω	-	0.9	-	
Fall time	t _f	NG-0022	-	0.03	-	

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

chip only

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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